



LCP1521S/LCP152DEE

PROGRAMMABLE TRANSIENT VOLTAGE SUPPRESSOR FOR SLIC PROTECTION

A.S.D.™

PRELIMINARY DATASHEET

FEATURES

- Dual programmable transient suppressor
- Wide negative firing voltage range:
 $V_{MGL} = -150\text{ V max.}$
- Low dynamic switching voltages: V_{FP} and V_{DGL}
- Low gate triggering current: $I_{GT} = 5\text{ mA max}$
- Peak pulse current: $I_{PP} = 30\text{ A (10/1000 }\mu\text{s)}$
- Holding current: $I_H = 150\text{ mA min}$
- Low space consuming package

DESCRIPTION

These devices have been especially designed to protect new high voltage, as well as classical SLICs, against transient overvoltages.

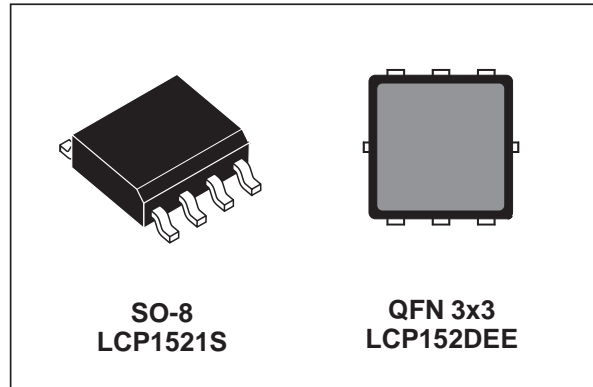
Positive overvoltages are clamped by 2 diodes. Negative surges are suppressed by 2 thyristors, their breakdown voltage being referenced to $-V_{BAT}$ through the gate.

These components present a very low gate triggering current (I_{GT}) in order to reduce the current consumption on printed circuit board during the firing phase.

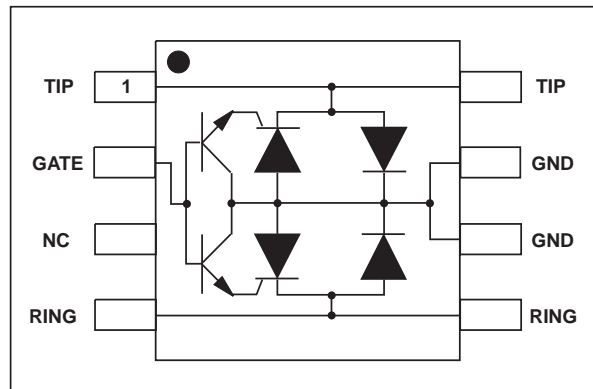
A particular attention has been given to the internal wire bonding. The Kelvin method configuration ensures reliable protection, reducing the overvoltage introduced by the parasitic inductances of the wiring, especially for very fast transients.

BENEFITS

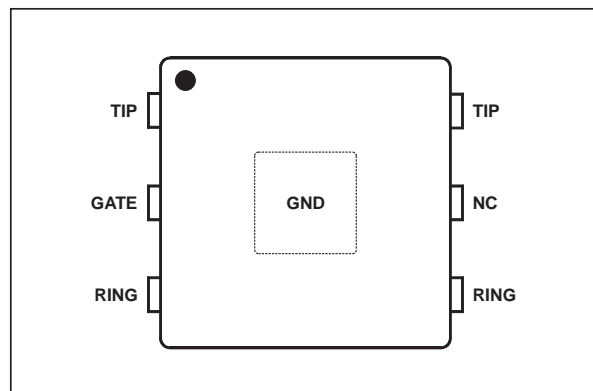
Trisils are not subject to ageing and provide a fail safe mode in short circuit for a better protection. Trisils are used to help equipment to meet various standards such as UL1950, IEC950 / CSA C22.2, UL1459 and FCC part68. Trisils have UL94 V0 resin approved (Trisils are UL497B approved (file: E136224)).



FUNCTIONAL DIAGRAM (LCP1521S)



FUNCTIONAL DIAGRAM (LCP152DEE)



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LCP1521S/LCP152DEE

IN COMPLIANCES WITH THE FOLLOWING STANDARDS

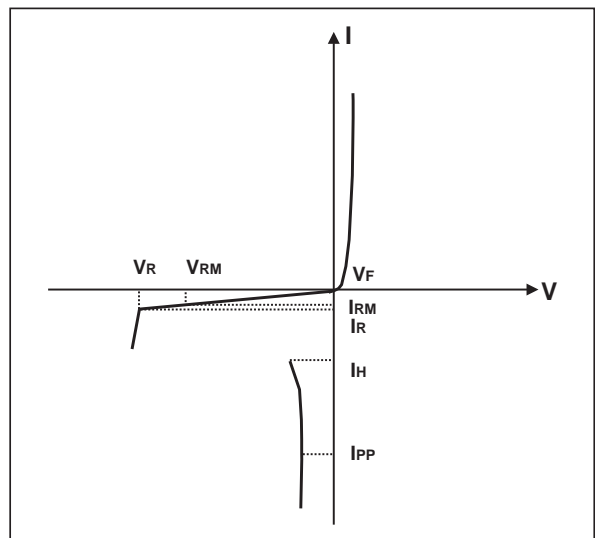
STANDARD	Peak Surge Voltage (V)	Voltage Waveform	Required peak current (A)	Current Waveform	Minimum serial resistor to meet standard (Ω)
GR-1089 Core First level	2500 1000	2/10 μ s 10/1000 μ s	500 100	2/10 μ s 10/1000 μ s	10 24
GR-1089 Core Second level	5000	2/10 μ s	500	2/10 μ s	20
GR-1089 Core Intra-building	1500	2/10 μ s	100	2/10 μ s	0
ITU-T-K20/K21	6000 1500	10/700 μ s	150 37.5	5/310 μ s	110 0
ITU-T-K20 (IEC61000-4-2)	8000 15000	1/60 ns	ESD contact discharge ESD air discharge		0 0
VDE0433	4000 2000	10/700 μ s	100 50	5/310 μ s	60 10
VDE0878	4000 2000	1.2/50 μ s	100 50	1/20 μ s	0 0
IEC61000-4-5	4000 4000	10/700 μ s 1.2/50 μ s	100 100	5/310 μ s 8/20 μ s	60 0
FCC Part 68, lightning surge type A	1500 800	10/160 μ s 10/560 μ s	200 100	10/160 μ s 10/560 μ s	22.5 15
FCC Part 68, lightning surge type B	1000	9/720 μ s	25	5/320 μ s	0

THERMAL RESISTANCE

Symbol	Parameter		Value	Unit
Rth (j-a)	Junction to ambient	SO-8	130	$^{\circ}$ C/W
		QFN 3x3	170	

ELECTRICAL CHARACTERISTICS (T_{amb} = 25 $^{\circ}$ C)

Symbol	Parameter
I _{GT}	Gate triggering current
I _H	Holding current
I _{RM}	Reverse leakage current LINE / GND
I _{RG}	Reverse leakage current GATE / LINE
V _{RM}	Reverse voltage LINE / GND
V _{GT}	Gate triggering voltage
V _F	Forward drop voltage LINE / GND
V _{FP}	Peak forward voltage LINE / GND
V _{DGL}	Dynamic switching voltage GATE / LINE
V _{GATE}	GATE / GND voltage
V _{RG}	Reverse voltage GATE / LINE
C	Capacitance LINE / GND



2 - PARAMETERS RELATED TO THE PROTECTION THYRISTOR ($T_{amb} = 25^{\circ}\text{C}$ unless otherwise specified)

Symbol	Test conditions		Min	Max	Unit
I_{GT}	$V_{GND/LINE} = -48\text{V}$		0.1	5	mA
I_H	$V_{GATE} = -48\text{V}$ (note 2)		150		mA
V_{GT}	at I_{GT}			2.5	V
I_{RG}	$V_{RG} = -150\text{V}$ $V_{RG} = -150\text{V}$	$T_c=25^{\circ}\text{C}$ $T_c=85^{\circ}\text{C}$		5 50	μA
V_{DGL}	$V_{GATE} = -48\text{V}$ (note 3) 10/700 μs 1.5kV $R_s = 10\Omega$ $I_{pp} = 30\text{A}$ 1.2/50 μs 1.5kV $R_s = 10\Omega$ $I_{pp} = 30\text{A}$ 2/10 μs 2.5kV $R_s = 62\Omega$ $I_{pp} = 38\text{A}$			7 10 25	V

Note 2: see functional holding current (I_H) test circuit

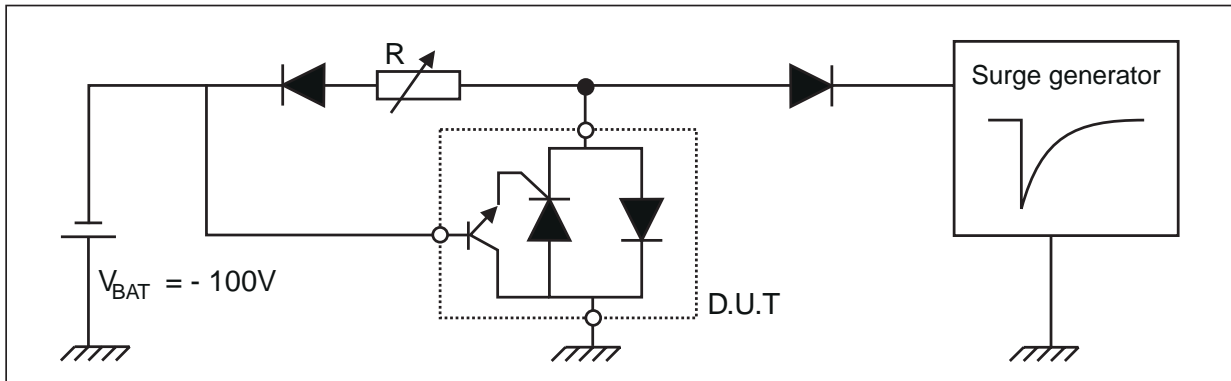
Note 3: see test circuit for V_{DGL}

The oscillations with a time duration lower than 50ns are not taken into account

3 - PARAMETERS RELATED TO DIODE AND PROTECTION THYRISTOR ($T_{amb} = 25^{\circ}\text{C}$, unless otherwise specified)

Symbol	Test conditions		Typ.	Max.	Unit
I_{RM}	$V_{GATE/LINE} = -1\text{V}$ $V_{RM} = -150\text{V}$ $V_{GATE/LINE} = -1\text{V}$ $V_{RM} = -150\text{V}$	$T_c=25^{\circ}\text{C}$ $T_c=85^{\circ}\text{C}$		5 50	μA
C	$V_R = 50\text{V}$ bias, $V_{RMS} = 1\text{V}$, $F = 1\text{MHz}$ $V_R = 2\text{V}$ bias, $V_{RMS} = 1\text{V}$, $F = 1\text{MHz}$		15 35		pF

FUNCTIONAL HOLDING CURRENT (I_H) TEST CIRCUIT : GO-NO GO TEST

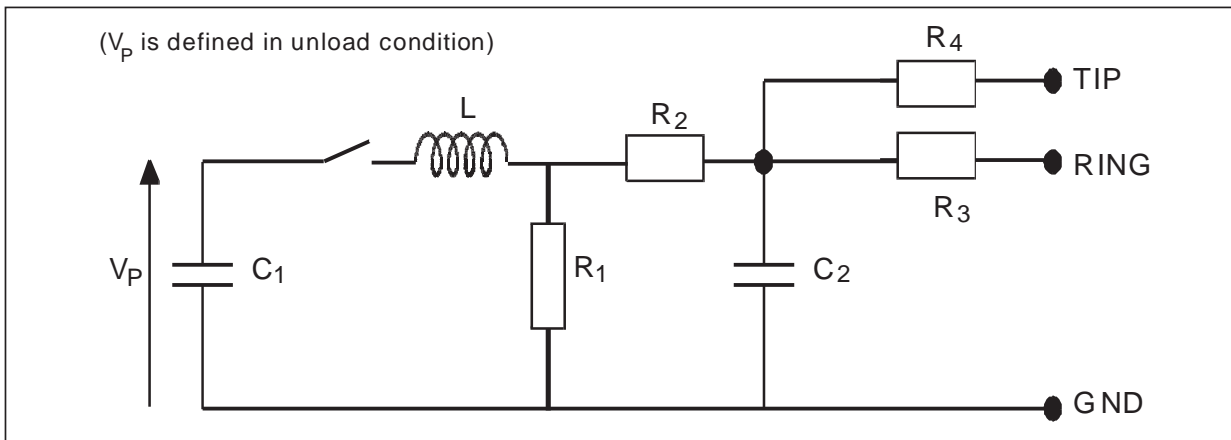


This is a GO-NO GO test which allows to confirm the holding current (I_H) level in a functional test circuit.

TEST PROCEDURE :

- Adjust the current level at the I_H value by short circuiting the D.U.T.
- Fire the D.U.T. with a surge current : I_{PP} = 10A, 10/1000μs.
- The D.U.T. will come back to the off-state within a duration of 50ms max.

TEST CIRCUIT FOR V_{FP} AND V_{DGL} PARAMETERS



Pulse (μs)		V _p (V)	C ₁ (μF)	C ₂ (nF)	L (μH)	R ₁ (Ω)	R ₂ (Ω)	R ₃ (Ω)	R ₄ (Ω)	I _{PP} (A)	R _s (Ω)
t _r	t _p										
10	700	1500	20	200	0	50	15	25	25	30	10
1.2	50	1500	1	33	0	76	13	25	25	30	10
2	10	2500	10	0	1.1	1.3	0	3	3	38	62

TECHNICAL INFORMATION

Fig. A1: LCP152 concept behavior.

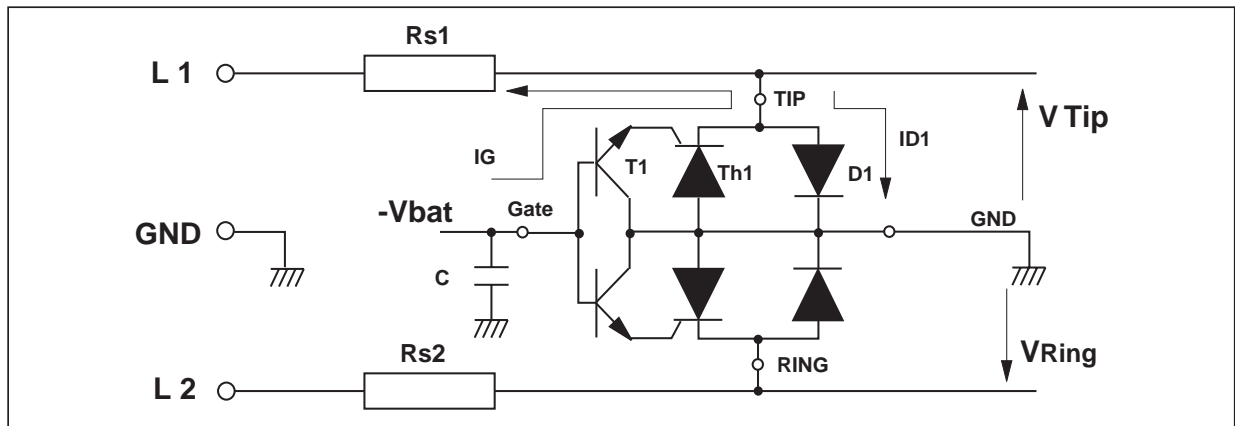
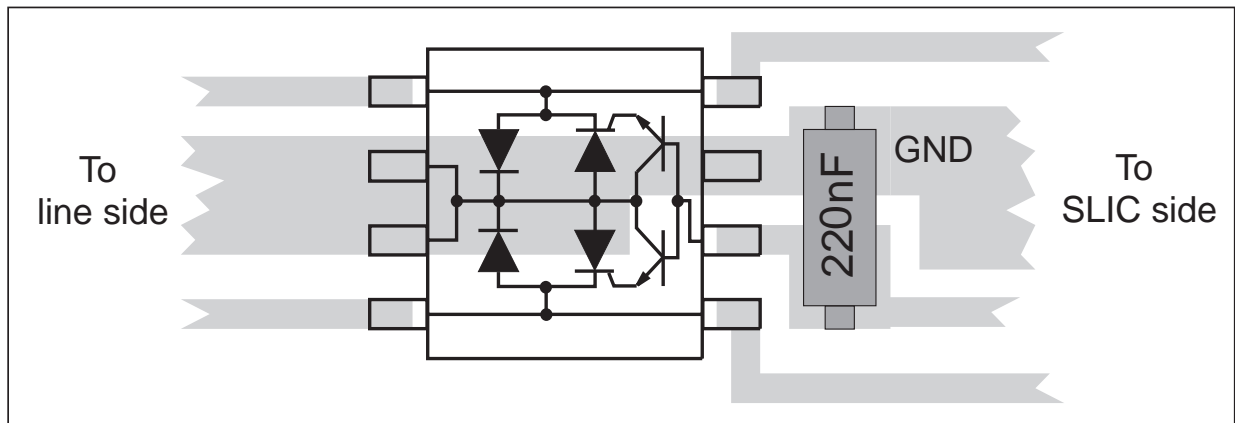


Figure A1 shows the classical protection circuit using the LCP152 crowbar concept. This topology has been developed to protect the new high voltage SLIC's. It allows to program the negative firing threshold while the positive clamping value is fixed at GND.

When a negative surge occurs on one wire (L1 for example) a current I_G flows through the base of the transistor T1 and then injects a current in the gate of the thyristor Th1. Th1 fires and all the surge current flows through the ground. After the surge when the current flowing through Th1 becomes less negative than the holding current I_H , then Th1 switches off.

When a positive surge occurs on one wire (L1 for example) the diode D1 conducts and the surge current flows through the ground.

Fig. A2: Example of PCB layout based on LCP152 protection.



In order to minimize the remaining voltage across the SLIC inputs during the surge, the TIP and RING pins of the LCP152 are doubled (Pins 1 and 8 for TIP / Pins 4 and 5 for RING).

This fact allows the board designer to connect the tracks like in figure A2. With such a PCB design, the extra voltages caused by track stray inductance remain located on the line side of the LCP and do not affect the SLIC side.

The capacitor C is used to speed up the crowbar structure firing during the fast surge edges.

This allows to minimize the dynamical breakover voltage at the SLIC Tip and Ring inputs during fast strikes. Note that this capacitor is generally present around the SLIC - Vbat pin.

So to be efficient it has to be as close as possible from the LCP152 Gate pin and from the reference ground track (or plan) (see Fig. A2). The optimized value for C is 220nF.

The series resistors Rs1 and Rs2 designed in figure A1 represent the fuse resistors or the PTC which are mandatory to withstand the power contact or the power induction tests imposed by the various country standards. Taking into account this fact the actual lightning surge current flowing through the LCP is equal to:

$$I_{\text{surge}} = V_{\text{surge}} / (R_g + R_s)$$

With V_{surge} = peak surge voltage imposed by the standard.

R_g = series resistor of the surge generator

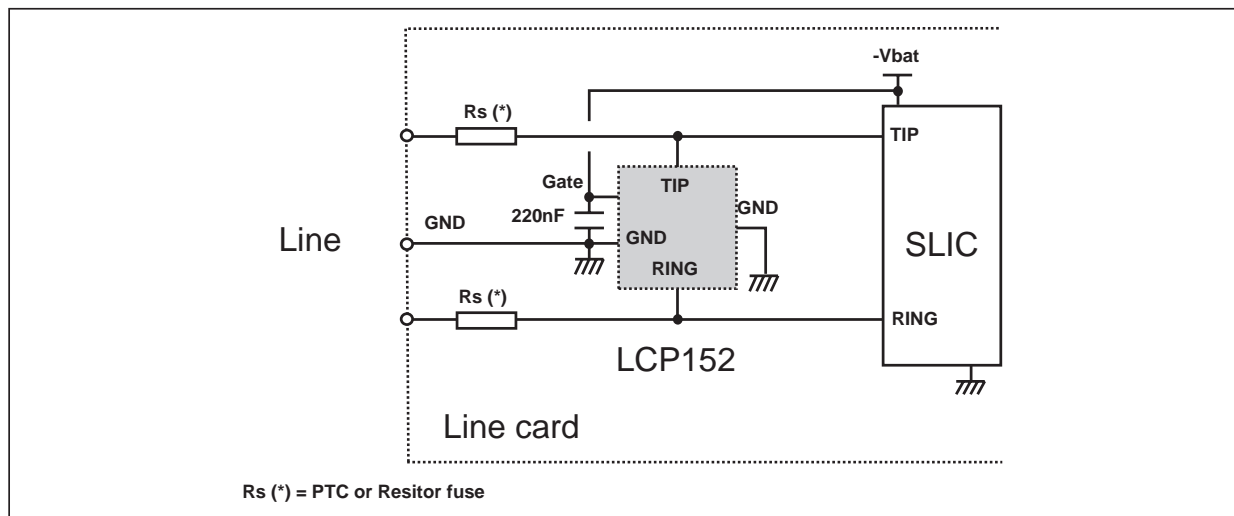
R_s = series resistor of the line card (e.g. PTC)

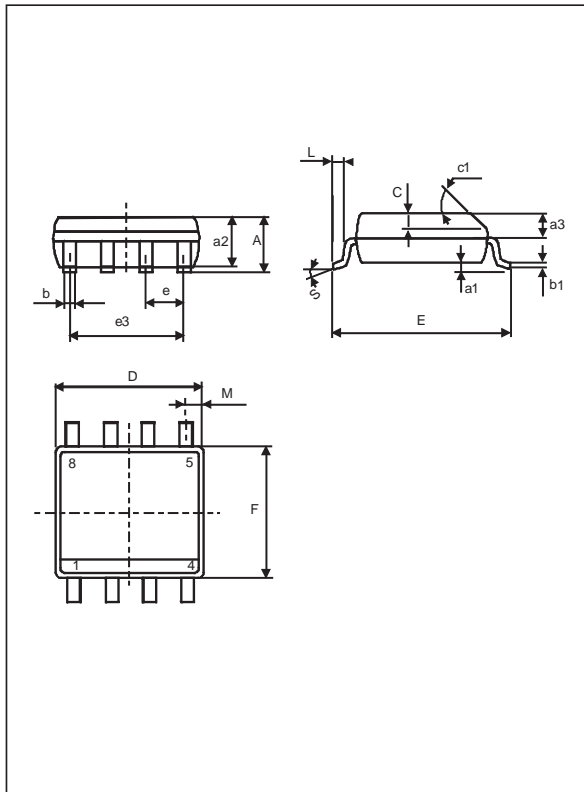
e.g. For a line card with 30Ω of series resistors which has to be qualified under GR1089 Core 1000V 10/1000μs surge, the actual current through the LCP152 is equal to:

$$I_{\text{surge}} = 1000 / (10 + 30) = \mathbf{25A}$$

The LCP152 is particularly optimized for the new telecom applications such as the fiber in the loop, the WLL, the remote central office. In this case, the operating voltages are smaller than in the classical system. This makes the high voltage SLICs particularly suitable. The schematics of figure A3 gives the most frequent topology used for these applications.

Fig. A3: Protection of high voltage SLIC.



PACKAGE MECHANICAL DATA
 SO-8 (Plastic)


REF.	DIMENSIONS					
	Millimetres			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A			1.75			0.069
a1	0.1		0.25	0.004		0.010
a2			1.65			0.065
a3	0.65		0.85	0.025		0.033
b	0.35		0.48	0.014		0.019
b1	0.19		0.25	0.007		0.010
C	0.25	0.50	0.50	0.010		0.020
c1	45° (typ)					
D	4.8		5.0	0.189		0.197
E	5.8		6.2	0.228		0.244
e		1.27			0.050	
e3		3.81			0.150	
F	3.8		4.0	0.15		0.157
L	0.4		1.27	0.016		0.050
M			0.6			0.024
S	8° (max)					

Order code	Marking	Package	Weight	Base qty	Delivery mode
LCP1521S	CP152S	SO-8	0.08 g	100	Tube
LCP1521SRL	CP152S	SO-8	0.08 g	2500	Tape & Reel
LCP152DEERL	CP15	QFN 3x3	0.022 g	3000	Tape & Reel

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